

| | | | | |
|-----------------------------------|--|-------------------------|---|--|
| Notice of References Cited | | Application/Control No. | Applicant(s)/Patent Under Reexamination | |
| | | 10/634,301 | TANAKA ET AL. | |
| Examiner | | Art Unit | Nitin Patel | |
| | | 2673 | Page 1 of 1 | |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|---------------------|----------------|
| * | A | US-5,136,516 | 08-1992 | Twombly, Jeffrey G. | 701/20 |
| * | B | US-5,130,827 | 07-1992 | Pavone et al. | 349/68 |
| * | C | US-4,814,757 | 03-1989 | Patterson et al. | 345/40 |
| * | D | US-6,333,697 | 12-2001 | Kumazawa et al. | 340/815.4 |
| * | E | US-6,667,726 | 12-2003 | Damiani et al. | 345/1.1 |
| * | F | US-6,693,523 | 02-2004 | Abel et al. | 340/461 |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| | | |
|---|---|---|
| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.